

Unprecedented speed

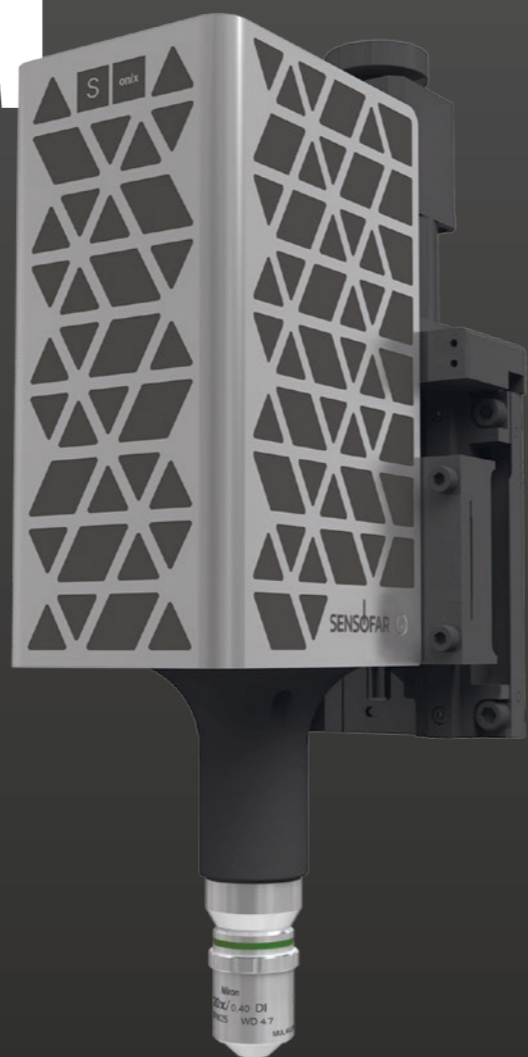
The **S onix** provides the speed needed for a high-throughput industrial metrology system. With its high-speed camera and optimized optical and mechanical design, the **S onix** represents our fastest interferometric system. System noise is maintained with the added bonus of improved resistance against vibration.

X9
Faster
interferometer

Resistance to
vibration

Compact
design

AUTOMATIC
3D



Objective lenses

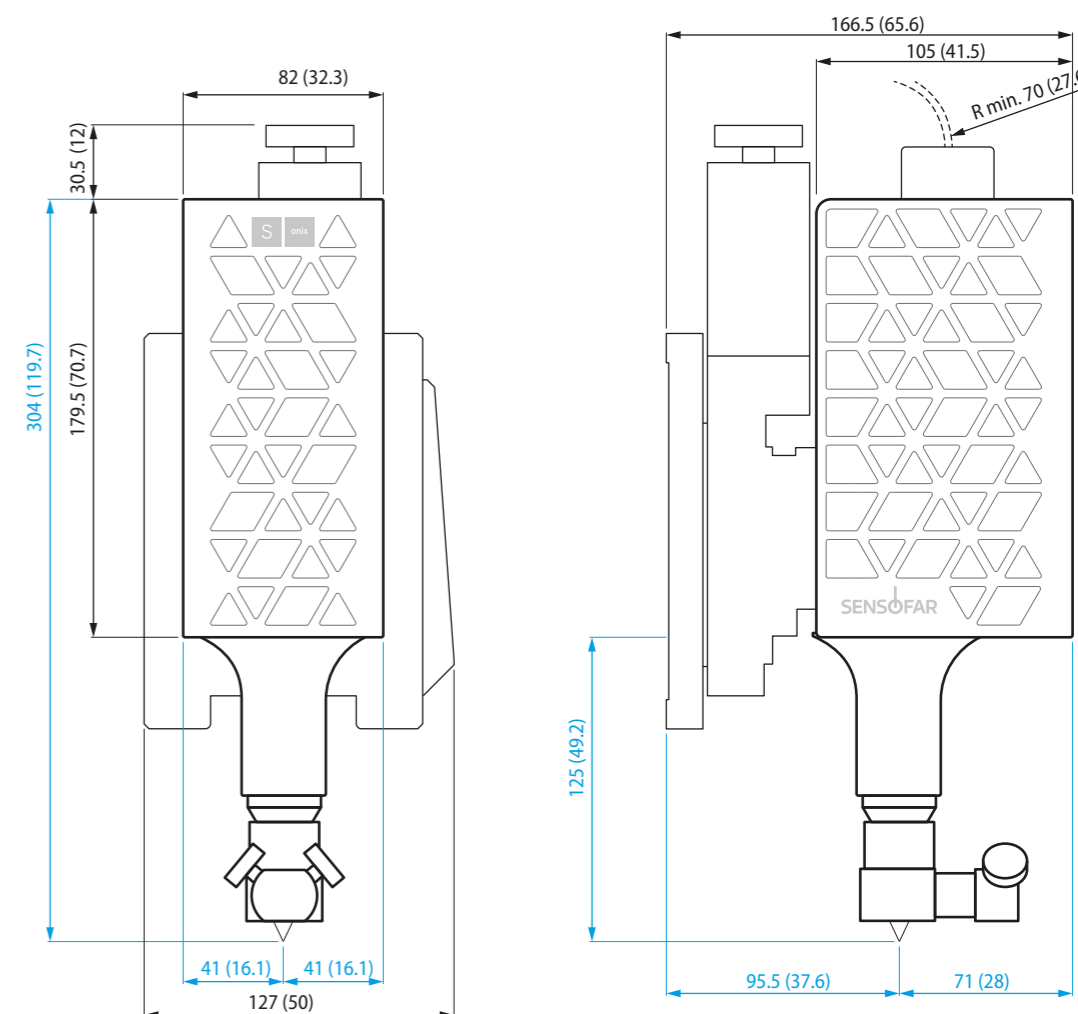
Magnification	Interferometric					
	2.5X	5X	10X	20X	50X	100X
NA	0.075	0.13	0.30	0.40	0.55	0.70
WD (mm)	10.3	9.3	7.4	4.7	3.4	2.0
FOV ¹ (μm)	5040 x 3780	2520 x 1890	1260 x 945	630 x 472	252 x 189	126 x 94
Spatial sampling ² (μm)	7.88	3.94	1.97	0.98	0.39	0.19
Optical resolution ³ (μm)	7.62	3.81	1.91	0.95	0.38	0.23
Vertical resolution ⁴ (nm)	1					
Maximum slope ⁵ (°)	3	8	14	21	25	42

System specifications

Measuring principle	CSI
Measurement types	Image, 3D and 3D thickness
Camera	640 x 480 pixels
Vertical scan range	Linear stage: 40 mm range; 2 nm resolution
Max. Z measuring range	7 mm
LED light sources	White (575 nm) and green (532 nm)
Nosepiece	1 position (default) or 6 manual position (optional)
Sample reflectivity	0.05 % to 100%
Advanced Software Analysis	Inc: SensoVIEW; Op: SensoPRO, SensoMAP
Software communication	DLL (C++ or C#, Windows 10® - 64 bits) XML (any operating system)
Computer	Latest INTEL processor
Operating system	Microsoft Windows 10®, 64 bit
Cable Length	5, 15 or 20 m
Environment	Temperature 10 °C to 35 °C; Humidity <80 % RH; Altitude <2000 m

Dimensions mm

Weight 3.6 kg (7.9 lbs)



Head dimensions

Working distances

1 Maximum field of view with 1/3" camera and 0.375X optics. **2** Pixel size on the surface. **3** L&S: Line and Space, half of the diffraction limit according to the Rayleigh criterion. Values for green LED. Spatial sampling could limit the optical resolution. **4** System noise measured as the difference between two consecutive measurements of a calibration mirror placed perpendicular to the optical axis. Values obtained in a VC-E vibration environment. **5** On smooth surfaces.